

# VIGO Laboratory for Electron Microscopy Transmission electron microscope



## JEOL JEM-2010F Specifications

<b>JEOL JEM-2010F Transmission Electron Microscope</b>	
<b>Specifications:</b>	
<b>Manufacturer:</b>	JEOL
<b>Type:</b>	Field Emission Transmission Electron Microscope
<b>Resolution</b>	Lattice image: 0.1 nm Point image: 0.19 nm
<b>Accelerating voltage</b>	80-200kV Stability: 2 pApm/min
<b>Magnification:</b>	50 to 1,500,000 in TEM Mode 16,000,000 in STEM mode Max
<b>Emitter:</b>	Thermal Field Emission FEG ZrO/W (100) Schottky
<b>Imaging modes</b>	MAG, Low MAG, SA MAG SA DIF, HD DIF, HR DIF
<b>Beam modes</b>	TEM, STEM EDS (Microanalysis mode) NBD (Nanometer-beam electron diffraction) CBD (Convergent-beam electron diffraction)
<b>Specimen</b>	3.05 mm Diameter
<b>Tilt Angle:</b>	X: $\pm 30^\circ$ , Y: $\pm 30^\circ$
<b>Operation &amp; display system</b>	Fast TEM system software For Operation: 18.1inch, high resolution FPD For Observation: 18.1inch, high resolution FPD
<b>Image Acquisition:</b>	GATAN slow scan digital camera in TEM Mode, Oxford Inca Energy 200 TEM in STEM Mode & Plates
<b>Software</b>	Fast TEM, Digital Micrograph, Dif Pack, Inca
<b>Accessories:</b>	
<b>STEM</b>	Magnification: 16,000,000 Max
<b>Microanalysis:</b>	X-Ray detector (EDS) Oxford Inca Energy 200 TEM (Line scan, X-Ray Mapping, Phase Map...)
<b>High Angle Annular Dark Field Detector</b>	For STEM ( Dark Field & Bright Field tips)
<b>Cryotransfer holder</b>	Gatan 626
<b>Two tilt holder</b>	Low background ( Microanalysis)